


<b>Search Notes</b>  	<b>Application/Control No.</b>  10762814	<b>Applicant(s)/Patent Under Reexamination</b>  BAU, DAVID
	<b>Examiner</b>  Qing Chen	<b>Art Unit</b>  2191

SEARCHED			
Class	Subclass	Date	Examiner
717	100,114-123	4/25/2009	/QC/

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) -- See Search History Printout	4/24/2009	/QC/
717/100,114-123 (limited class search)	4/25/2009	/QC/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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